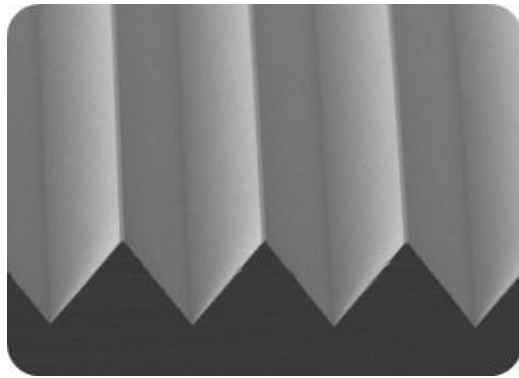
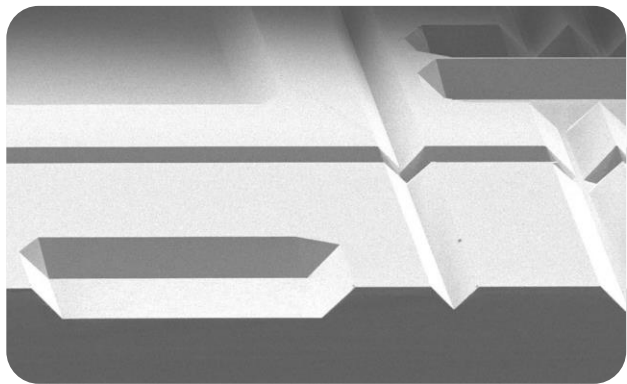
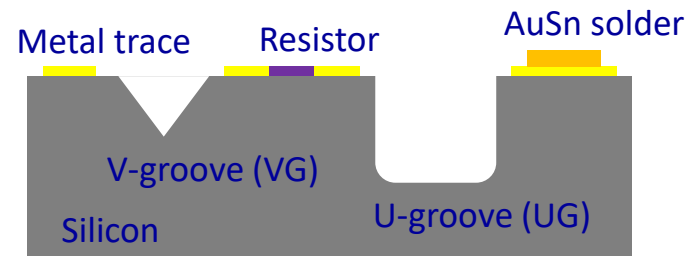


Process Platform: Silicon Optical Bench

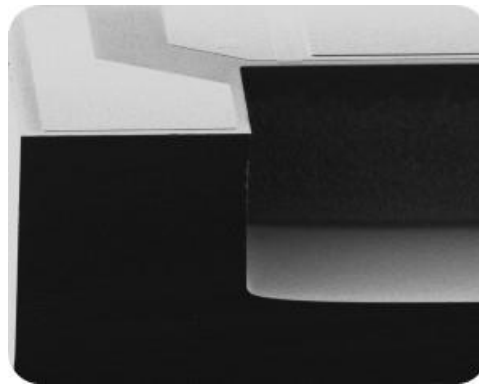
- High precision VG with 45° or 54.7° slope
- Potential to integrate with thin-film resistor, metal trace, and solder



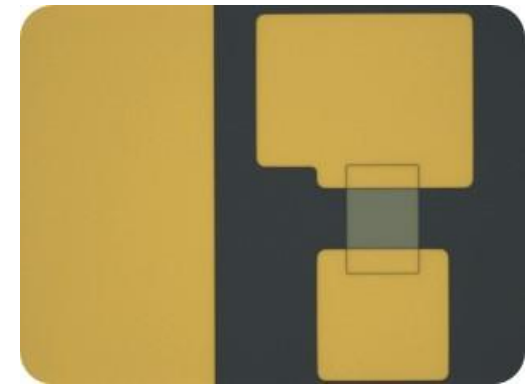
54.7° V-groove



45° V-groove



U-groove



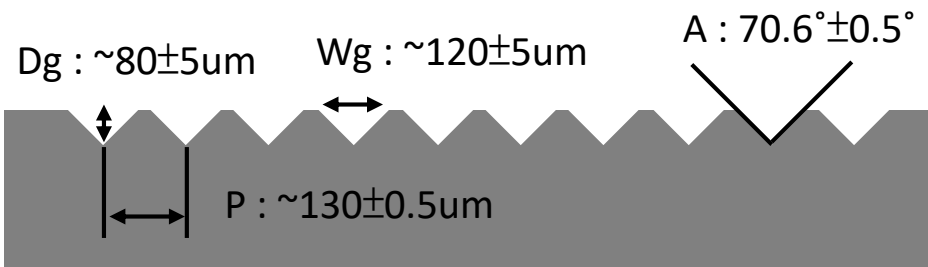
Optional metal layers



Process Platform: Silicon Optical Bench

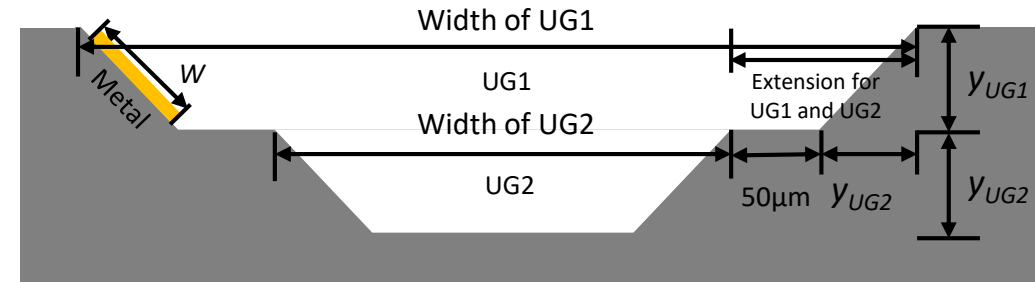
54.7° VG Dimension:

- Groove Depth (D_g): target $\pm 5\mu\text{m}$
- Groove Width (W_g): target $\pm 5\mu\text{m}$
- Groove Pitch (P): target $\pm 0.5\mu\text{m}$
- Groove Angle (A): 70.6 ± 0.5 degree



45° VG/UG Dimension:

- Depth variation of UG1: $\pm 10\%$
- Depth variation of UG2: $\pm 10\%$
- Width variation of UG1: STD~3%
- Width variation of UG2: STD~5%
- Width variation of Metal: $\pm 10\%$



Process Platform: Silicon Optical Bench

Thin Film Resistor (TaAl):

- TFR max. sheet resistance(R_s): 50 ohm/sq
- TFR min. width(Z)/length(Y): 10um / 70um
- UBM min. width(U)/length(V): 150um / 150um
- Min. width of overlay(W): 10um
- Resistance calculation: $((Y-2*W)/U)*R_s$

